

X-ray Laue Back-scattered Camera

The high resolution Laue X-ray camera allows a digital Laue diffraction pattern to be recorded with a resolution of 2774 x 1843 pixels and 14-bit digitization.

The X-ray passes through the camera and is collimated down < 1mm diameter. The active area input dimension is similar to that of Polaroid film i.e. 156 mm x 104.4 mm. Exposures from a few seconds up to >30 minutes can be adjusted during manual or automatic crystal orientations before being cut. Twinned structures occurring during crystal growth can be unveiled using a high resolution mode.

Upgrades from existing X-ray sources are made using high precision mechanics allowing accuracy down to 0.05 degrees. A micro-diffraction set-up for both laboratory and or synchrotron sources can be provided on demand. Active input area of approx. 155(h) x 105(v) 155(h) x 105(v) mm imaged on the sensor Minimum input sizes 57µ square, 2,774 x 1,843 pixels Selectable exposure from 1ms to 35 minutes On chip pixel addition allowing increased sensitivity at the expense of resolution 18-bit high precision acquisition mode 14-bit fast preview mode Automatic background subtraction mode PSEL acquisition Laue image processing software

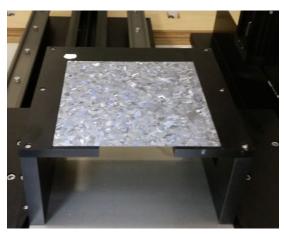
Realtime crystal orientation down to 0.1 degrees accuracy Misalignment measurements down to 0.5 degrees using PSEL software Two dimensional orientation mapping of polycrystalline silicon wafers High throughput sapphire sample screening. Heavy duty sample screening up tp 20kg

Specialist Camera Solutions

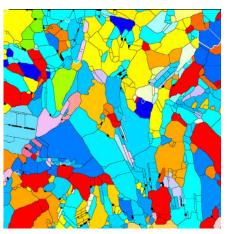
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PHOTONIC

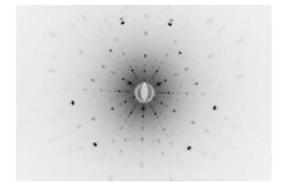
Application images for Laue X-ray camera



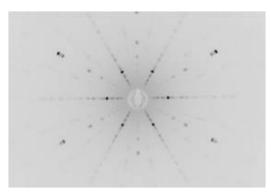
Polycrystalline silicone wafer scanner



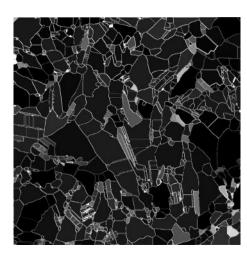
Two dimensional orientation map



Sapphire C-axis aligned



SiC Hex aligned



Poly crystalline Si Wafer



Standard Laue system outline

Detector Materials:

HgCdTe / CdTe GaAs InSb

Window Materials and piezo/ferro electric ceramics:

Al203 Quartz LiNb03

Metals and alloys:

Tungsten Molybdenum Nickel based alloys

Laser Materials:

YAG LuAg KTP

Thin films / semiconductor substrates:

AIN InP SiC

Magnetic and superconducting materials

YBCO/BSCCO/HBCCO FeSe NbSn / NbTi Scintillator materials:

BGO / LYSO CdWO4 BaF2/CaF2

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